

Sheet 1 of 1

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

60091.00305

SERIAL NO.

10/829,424

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT

Ari TIKKA et al.

FILING DATE

April 22, 2004

GROUP

2621

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO PART.		
JTW	AG	EP 0 907 147 A2	April 7, 1999	European	—	—	X		
	AH								
	AI								
	AJ								
	AK								

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AL	
	AM	
	AN	
EXAMINER	<i>J. Whiphay</i>	DATE CONSIDERED 7/16/07
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)	ATTY. DOCKET NO. 60091.00305	SERIAL NO. 10/829,424 New Cont. Appln
	APPLICANT TIKKA et al	
	FILING DATE April 22, 2004	GROUP Not yet assigned


U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
JTW	AA	5,806,005	09/08/98	Hull et al	—	—	
	AB						
	AC						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO PART.		
JTW	AD	WO 01/45388 A2	06/21/01	WIPO	—	—	xx		
JTW	AE	EP 0 975 132 A1	01/26/00	European	—	—	xx		
JTW	AF	WO 01/58138 A1	08/09/01	WIPO	—	—	xx		
JTW	AG	EP 0 844 781 A2	05/27/98	European	—	—	xx		
JTW	AH	EP 1 028 569 A2	08/16/00	European	—	—	xx		
JTW	AI	EP 1 098 496 A2	05/09/01	European	—	—		xx	
JTW	AJ	EP 1 124 375 A3	08/16/01	European	—	—	xx		
JTW	AK	GB 2 354 657 A	03/28/01	United Kingdom	—	—	xx		

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

JTW	AL	PATENT ABSTRACTS OF JAPAN, VOL. 20000, NO. 9, October 13, 2000, & JP 2000 172596 A.
JTW	AM	PATENT ABSTRACTS OF JAPAN, JP 2001339489 A, February 7, 2001.
JTW	AN	PATENT ABSTRACTS OF JAPAN, JP 2000232680 A, August 22, 2000.
EXAMINER		
	DATE CONSIDERED 7/16/07	
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>		